

MT050WT SYSTEM NEW WAFER TESTER



STATIC VERIFICATIONS:

- $I_{ges}, I_{gds}, V_{geth}, V_{gsth}, I_{gt}, V_{gt}, I_{hold}, I_{latch}$: +/- 30V/1A
- $I_{ces}, I_{drm}, I_{rrm}, B_{vces}, V_{rrm}, V_{drm}$: up to 2.3kV /50mA
- $V_{ceon}/V_{dson}, V_f$: up to 10Amp (OPTION UP TO 200 A)
- Kelvin tests performed continuity check
- Up to **100 tests** in a single run
- **Results data collection**, export and statistical analysis, BIN summary, Wafer summary
- **Flexible Testprogram**: test sequence based on partial results (**Jump on Pass/Fail**)
- **Classes** can be defined upon test results using the Matching **editor**.
- TTL/IEEE wafer prober interface

DYNAMIC VERIFICATIONS:

- Turn ON/OFF switching , T_{rr}/Q_{rr} on single die measurement (coming soon)